



HEIWA.014AU

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant	:	Shuuske Kantake	)	Group Art Unit 2857
			)	
Serial No.	:	10/500,427	)	
			)	
Filed	:	June 28, 2004	)	
			)	
For	:	TEST EQUIPMENT FOR LSI AS	)	
		A DEVICE UNDER TEST,	)	
		JITTER ANALYZER, AND PHASE	)	
		DIFFERENCE DETECTOR	)	
			)	
Examiner	:	Mohamed Charioui	)	
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AMENDMENT

Hon. Commissioner  
of Patents and Trademarks  
Alexandria, VA 22313-1450

Dear Sir:

This amendment is submitted for the above-identified patent application in response to the office action from the United States Patent and Trademark Office mailed September 22, 2005. Please make the following changes.